## Quinoidal Oligoquinoline: A Novel Quinodimethane Exhibiting High Electroluminescence Efficiency and p-Channel Field Effect Charge Transport

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Single Crystal Structure. Single crystals of 5 suitable for the determination of X-ray crystal structure were grown by slow evaporation of CHCl<sub>3</sub>/methanol solution. 5 was obtained as white needles and was found to have a monoclinic crystal with unit cell parameters: a = 17.7390(7) Å, b = 5.9890(2) Å, c = 25.1160(10) Å, and  $\beta = 120.6770(16)$ . The space group was P c. The structure was refined to a final residual of  $R_1 = 6.77\%$ .

Materials. All reagents were purchased from Aldrich and used as received.

**6,6'-Bis(2-(diphenylmethylene)-4-phenylquinoline) (5).** 0.507 g (2.42 mmol) of 1,1diphenylacetone (**3**), 0.475 g (1.21 mmol) of 3,3'-dibenzoylbenzidine (**4**), 3 g of diphenylphosphate, and 5 mL toluene were added to a dry reaction flask. The flask was purged with argon for 20 minutes and the temperature was gradually raised to 120 °C and stirred for 24 hr. The reaction mixture was precipitated into 10% triethylamine/ethanol and collected by vacuum filtration.<sup>10</sup> The precipitate was passed through silica gel column via flash chromatography to remove impurities. The resulting product was then recrystallized twice from tetrahydrofuran/methanol solutions. 0.725 g (81 %) of **5** was recovered as white needles. <sup>1</sup>H-NMR (CDCl<sub>3</sub>):  $\delta$  ppm = 8.22 (d, 2H), 8.11 (s, 2H), 8.04 (d, 2H), 7.99 (s, 2H), 7.48 (m, 10H), 7.43 (m, 20H), 5.89 (s, 2H). HRMS (FAB) calcd for C<sub>56</sub>H<sub>40</sub>N<sub>2</sub> 740.9566, found 740.9562.

**6,6'-Bis(2-(diphenylmethylene)-4-phenylquinoline) (6, BQPQ).** 1.45 g (1.96 mmol) of **5** and 0.56 g (2.5 mmol) 2,3-dichloro-5,6-dicyano-1,4-benzoquinone were refluxed in anhydrous acetonitrile under argon for 2 h. The resulting solid was collected by filtration, dried, and chromatographed in silica gel with CH<sub>2</sub>Cl<sub>2</sub>. Products were then recrystallized twice from CHCl<sub>3</sub>/MeOH mixtures. 0.745 g (52 %) was recovered as a yellow solid. <sup>1</sup>H-NMR (CDCl<sub>3</sub>):  $\delta$  ppm = 8.76 (d, 2H), 8.59 (s, 2H), 8.09 (d, 2H), 7.91 (s, 2H), 7.71 (m, 10H), 7.50 (m, 20H). HRMS (FAB) calcd for C<sub>56</sub>H<sub>38</sub>N<sub>2</sub> 738.9407, found 738.9405.

**General**. <sup>1</sup>H NMR and <sup>13</sup>C-NMR spectra were recorded on a Bruker DRX-499 at 499 MHz using CDCl<sub>3</sub> as the solvent. Fourier transformation infrared (FT-IR) spectroscopy was done as a film on a KBr plate using a Perkin-Elmer 1720 FT-IT spectrometer. Thermogravimetric analysis of the molecules was conducted on a TA Instruments Q50 TGA. A heating rate of 10 °C/min under flowing N<sub>2</sub> was used with runs being conducted from room temperature to 600 °C.

**Photophysics.** Optical absorption spectra were obtained by using a Lambda-900 UV/vis/near-IR spectrophotometer (Perkin-Elmer). Photoluminescence spectra were carried out on a PTI QuantaMaster model QM-2001-4 spectrofluorometer (Photon Technology International Inc. Ontario, Canada). To measure the PL quantum yields ( $\phi_f$ ), oligoquinoline solutions in spectral grade toluene were prepared. The concentration (~10<sup>-6</sup> M) was adjusted so that the absorbance of the solution was lower than 0.1. A 5 x 10<sup>-6</sup> M solution of 9,10-diphenylanthracene in toluene was used as a standard ( $\phi_f = 0.93$ ). All the

solutions were degassed with high-purity nitrogen for at least 20 min before spectral acquisition.

**Cyclic Voltammetry.** Cyclic voltammetry experiments were done on an EG&G Princeton Applied Research Potentiostat/Galvanostat (Model 273A). Data were collected and analyzed by the Model 270 Electrochemical Analysis System Software on a PC computer. A three-electrode cell was used in all experiments as previously described.<sup>11</sup> Platinum wire electrodes were used as both counter and working electrodes and silver/silver ion (Ag in 0.1 M AgNO<sub>3</sub> solution, Bioanalytical System, Inc.) was used as a reference electrode. Ferrocene/ferrocenium (Fc/Fc<sup>+</sup>) redox couple was used as an internal standard and the potential values, thus, obtained in reference to Ag/Ag<sup>+</sup> electrode were converted to the saturated calomel electrode (SCE) scale. Solution cyclic voltammetry was carried out on a millimolar solution of BQPQ in DMF solvent containing TBAPF<sub>6</sub> (0.1 M) as an electrolyte. The solution in the three-electrode cell was purged with ultrahigh-purity N<sub>2</sub> for 10-15 minutes before each experiment and a blanket of N<sub>2</sub> was used during the experiment.

Fabrication and Characterization of OLEDs. The OLEDs were fabricated using BQPQ as an emissive material. Indium-tin oxide (ITO)-coated glass substrates (Delta Technologies Ltd., Stillwater, MN) were cleaned sequentially in ultrasonic baths of 2-propanol/deionized water (1:1 volume) mixture, toluene, deionized water, and acetone, then dried at 60 °C in vacuum overnight. A ~1wt% poly(ethylenedioxythiophene)/ poly(styrene sulfonate) blend (PEDOT) dispersion in water was filtered through a 0.45  $\mu$ m PVDF syringe filter. A 40 nm thick layer was then spin cast onto the ITO-coated glass to act as a hole injection layer and dried at 200 °C for 15 minutes under vacuum. A

20nm thick poly(N-vinylcarbazole) (PVK) hole-transport/electron-blocking layer was spin coated from a 1 wt% toluene solution onto the PEDOT layer and dried at 60 °C for 4 hour under vacuum. Films (35-45 nm) of BQPQ were evaporated from resistively heated quartz crucibles at a rate of 0.2-0.3 nm/s in a vacuum evaporator (Edwards Auto 306) at a base pressure of  $<3 \times 10^{-6}$  Torr onto the PVK layer. The chamber was vented with air to load the cathode materials, pumped down to  $\sim 3 \times 10^{-6}$  Torr, and a 2 nm thick lithium fluoride layer followed by a 120nm thick aluminum layer were deposited through a shadow mask to form active diode areas of  $0.2 \text{ cm}^2$ . The film thicknesses were measured by an Alpha-Step 500 surface profiler (KLA Tencor, Mountain View, CA). Electroluminescence spectra were obtained using a PTI QM-2001-4 spectrofluorimeter. Current-voltage characteristics of the LEDs were measured using a HP4155A semiconductor parameter analyzer (Yokogawa Hewlett-Packard, Tokyo). The luminance was simultaneously measured using a model 370 optometer (UDT instruments, Baltimore, MD) equipped with a calibrated luminance sensor head (model 211) and a 5x objective lens. The device external quantum efficiency was calculated using procedures reported previously.<sup>14</sup> All the device fabrication and characterization steps were done under ambient laboratory conditions.

**Fabrication and Characterization of Thin Film Transistors.** The thin film field-effect transistors were fabricated by using a bottom contact geometry. Heavily doped Si with a conductivity of  $10^3$  S/cm was used as the gate electrode with a 300 nm thick SiO<sub>2</sub> layer as the gate dielectric. By means of photolithography and vacuum sputtering (2 ×  $10^{-6}$  Torr), two 90 nm thick gold electrodes (source and drain) with 10 nm thick Ti-W alloy adhesive layer were fabricated onto the SiO<sub>2</sub>/Si substrates. A channel length (*L*) of 25 µm and a

channel width (W) of 500  $\mu$ m were used. A gold contact pad was also deposited on the gate electrode to make ohmic contact. Electrical characteristics of the devices were measured using a Keithley 4200 semiconductor parameter analyzer (Keithley Instruments, Inc., Cleveland, OH). All fabrication and measurements were done under ambient laboratory conditions.

Surface Treatment of SiO<sub>2</sub> and Thin Film Deposition. SiO<sub>2</sub> surface was treated with hexamethyldisilazane vapor at  $150^{\circ}$ C for 5 min. The SiO<sub>2</sub> surface was characterized before and after modification by measuring the advancing contact angle of a water drop on the SiO<sub>2</sub> surface. Before treatment, the contact angle was around 10-15°, indicating a hydrophilic surface. After treatment with HMDS the water contact angle increased to 50°. The thin-films of BQPQ were deposited by vacuum evaporation (<10<sup>-6</sup> torr).

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Device Structure <sup>a</sup>		Von <sup>b</sup>	Drive	J <sub>max</sub> <sup>c</sup>	L <sub>max</sub> <sup>d</sup>	LE <sub>max</sub>	EL	CIE 1931
		(V)	Voltage	$(mA/m^2)$	$(cd/m^2)$	(@ L)	$\lambda_{max}$	x,y
			(V)			(cd/A)		
Ι	BQPQ	2.2	5.3	234	180	0.1	512	0.27, 0.57
						(135)		
Π	BQPQ/TPBI	2.3	8	500	6030	5.0	507	0.25, 0.60
						(160)		
III	PEDOT/PVK/BQPQ	3.5	11	202	1615	1.1	512	0.28, 0.59
						(804)		
IV	PEDOT/PVK/BQPQ/TPBI	3.5	13.7	500	16265	5.9	510	0.30, 0.58
						(2035)		

**Table S1** Electroluminescent Properties of BQPQ OLEDs.

<sup>a</sup>All devices used ITO as the anode and LiF/Al as the cathode. <sup>b</sup>Turn-on voltage (at which

EL is visible to the eye). <sup>c</sup>Current Density. <sup>d</sup>Luminance.



Figure S1 Second heating DSC scan of BQPQ at a heating rate of 10 °C/min in nitrogen.



Figure S2 TGA scan of BQPQ at a heating rate of 10 °C/min in nitrogen.



**Fig. S3** Cyclic voltammogram of BQPQ in 0.1M in DMF/0.1 M TBAPF<sub>6</sub> MeCN. Scan rate = 300 mV/sec.



**Fig S4** Absorption and photoluminescence (PL) spectra of **5** in  $10^{-6}$  M toluene solution and as a thin film.



Figure S5 Device schematic of a bottom contact organic field-effect transistor (OFET).